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Lee, I.; Iyer, R.K.;
Software Engineering, IEEE Transactions on
Volume 26, Issue 2, Feb. 2000 Page(s):113 - 127
Digital Object Identifier 10.1109/32.841113
AbstractPlus | References | Full Text: PDF(268 KB)   IEEE JNL

☐   **2. Defect prevention through defect prediction: a case study at Infosys**
Mohapatra, S.; Mohanty, B.;
Software Maintenance, 2001. Proceedings. IEEE International Conference on
7-9 Nov. 2001 Page(s):260 - 272
Digital Object Identifier 10.1109/ICSM.2001.972739
AbstractPlus | Full Text: PDF(82 KB)   IEEE CNF

☐   **3. ANN application in electronic diagnosis-preliminary results**
Andrejevic, M.; Litovski, V.;
Microelectronics, 2004. 24th International Conference on
Volume 2, 16-19 May 2004 Page(s):597 - 600 vol.2
AbstractPlus | Full Text: PDF(357 KB)   IEEE CNF

☐   **4. Systematic approach to modern corded telephone early commutation fail**
Verbitsky, D.E.; Comerford, T.N.;
Reliability and Maintainability Symposium, 1999. Proceedings. Annual
18-21 Jan. 1999 Page(s):84 - 90
Digital Object Identifier 10.1109/RAMS.1999.744101
AbstractPlus | Full Text: PDF(1296 KB)   IEEE CNF

☐   **5. Quality testing requires quality thinking**
Soden, J.M.; Hawkins, C.F.;
Test Conference, 1993. Proceedings., International
17-21 Oct. 1993 Page(s):596
Digital Object Identifier 10.1109/TEST.1993.470646
AbstractPlus | Full Text: PDF(96 KB)   IEEE CNF

☐   **6. Developing case-based reasoning systems: a case study in diagnosing b**
Watson, I.; Abdullah, S.;
Case Based Reasoning: Prospects for Applications, IEE Colloquium on
3 Mar 1994 Page(s):1/1 - 1/3
AbstractPlus | Full Text: PDF(16 KB)   IEE CNF

7. **A defect-tolerant design for full-wafer memory LSI**
Ueoka, Y.; Minagawa, C.; Oka, M.; Ishimoto, A.;
Solid-State Circuits, IEEE Journal of
Volume 19, Issue 3, Jun 1984 Page(s):319 - 324

AbstractPlus | Full Text: PDF(1128 KB)   IEEE JNL

8. **Some high-power window failures**
Vaughan, J.R.M.;
Electron Devices, IEEE Transactions on
Volume 8, Issue 4, Jul 1961 Page(s):302 - 308

AbstractPlus | Full Text: PDF(888 KB)   IEEE JNL

9. **Fault detection in programmable logic arrays**
Somenzi, F.; Gai, S.;
Proceedings of the IEEE
Volume 74, Issue 5, May 1986 Page(s):655 - 668

AbstractPlus | Full Text: PDF(1205 KB)   IEEE JNL

10. **Detection of wide-band E-M signals emitted from partial discharge occur wavelet transform**
Kawada, M.; Tungkanawanich, A.; Kawasaki, Z.-I.; Matsu-Ura, K.;
Power Delivery, IEEE Transactions on
Volume 15, Issue 2, April 2000 Page(s):467 - 471
Digital Object Identifier 10.1109/61.852970

AbstractPlus | References | Full Text: PDF(124 KB)   IEEE JNL

11. **Scaffold-based articular cartilage repair**
Capito, R.M.; Spector, M.;
Engineering in Medicine and Biology Magazine, IEEE
Volume 22, Issue 5, Sept.-Oct. 2003 Page(s):42 - 50
Digital Object Identifier 10.1109/MEMB.2003.1256271

AbstractPlus | References | Full Text: PDF(792 KB)   IEEE JNL

12. **Energy output degradation of Czochralski ruby lasers**
Stickley, C.M.; Miller, H.; Hoell, E.E.; Gallagher, C.C.; Bradbury, R.A.;
1967 International Electron Devices Meeting
Volume 13, 1967 Page(s):32 - 32

AbstractPlus | Full Text: PDF(112 KB)   IEEE CNF

13. **Crop Nutrition Diagnosis Expert System Based on Artificial Neural Netwc**
Haiyan Song; Yong He;
Information Technology and Applications, 2005. ICITA 2005. Third Internationa
Volume 1, 04-07 July 2005 Page(s):357 - 362
Digital Object Identifier 10.1109/ICITA.2005.108

AbstractPlus | Full Text: PDF(91 KB)   IEEE CNF

14. **Risk for alcoholism and developmental defects of specific brain structure morphometric study**
Antony, G.; Benegal, V.; Jayakumar, P.N.;
Biomedical Imaging: Macro to Nano, 2004. IEEE International Symposium on
15-18 April 2004 Page(s):229 - 232 Vol. 1
Digital Object Identifier 10.1109/ISBI.2004.1398516

AbstractPlus | Full Text: PDF(444 KB)   IEEE CNF

15. **Partial discharge weak spots localization in the stator insulation of runni generators**
van Breen, H.J.; Gulski, E.; Smit, J.J.;
Electrical Insulation Conference and Electrical Manufacturing & Coil Winding T
Conference, 2003. Proceedings
23-25 Sept. 2003 Page(s):43 - 46
Digital Object Identifier 10.1109/EICEMC.2003.1247851

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16. **PD inception conditions and PD pattern of defects in PILC**
Muramoto, Y.; Gulski, E.; Wester, F.J.; Smit, J.J.;
Solid Dielectrics, 2001. ICSD '01. Proceedings of the 2001 IEEE 7th Internatio
on
25-29 June 2001 Page(s):369 - 372
Digital Object Identifier 10.1109/ICSD.2001.955659

AbstractPlus | Full Text: PDF(384 KB)   IEEE CNF

17. **Bayesian networks and decision trees in the diagnosis of female urinary**
Hunt, M.; von Konsky, B.; Venkatesh, S.; Petros, P.;
Engineering in Medicine and Biology Society, 2000. Proceedings of the 22nd /
International Conference of the IEEE
Volume 1, 23-28 July 2000 Page(s):551 - 554 vol.1
Digital Object Identifier 10.1109/IEMBS.2000.900799

AbstractPlus | Full Text: PDF(348 KB)   IEEE CNF

18. **Recognition of defects in high voltage transmission lines using the acou**
corona effect
Tadeusiewicz, R.; Wszolek, T.; Izworski, A.; Wszolek, W.;
Neural Networks for Signal Processing X, 2000. Proceedings of the 2000 IEEE
Processing Society Workshop
Volume 2, 11-13 Dec. 2000 Page(s):869 - 875 vol.2
Digital Object Identifier 10.1109/NNSP.2000.890167

AbstractPlus | Full Text: PDF(368 KB)   IEEE CNF

19. **Perspectives of extreme HF-therapy in medicine**
Shakourov, M.Sh.; Makarov, A.G.; Morozov, G.A.;
Microwave Conference, 1999. Microwave & Telecommunication Technology. 1
International Crimean [In Russian with English abstracts]
13-16 Sept. 1999 Page(s):401 - 402
Digital Object Identifier 10.1109/CRMICO.1999.815286

AbstractPlus | Full Text: PDF(168 KB)   IEEE CNF

20. **Dynamic diagnosis of sequential circuits based on stuck-at faults**
Venkataraman, S.; Hartanto, I.; Kent Fuchs, W.;
VLSI Test Symposium, 1996., Proceedings of 14th
28 April-1 May 1996 Page(s):198 - 203
Digital Object Identifier 10.1109/VTEST.1996.510858

AbstractPlus | Full Text: PDF(496 KB)   IEEE CNF

21. **Categorizing light output degradation failures in LEDs using the relation:**
defect revealing mechanisms responsible for electroluminescence (EL),
cathodoluminescence (CL), EBIC, and reverse bias photoemission (RP)
Mann, R.S.; McElfresh, D.K.;
Reliability Physics Symposium, 1995. 33rd Annual Proceedings., IEEE Interna
4-6 April 1995 Page(s):177 - 186
Digital Object Identifier 10.1109/RELPHY.1995.513672

AbstractPlus | Full Text: PDF(2528 KB)   IEEE CNF

22. **Software defects and their impact on system availability-a study of field 1**
operating systems
Sullivan, M.; Chillarege, R.;
Fault-Tolerant Computing, 1991. FTCS-21. Digest of Papers., Twenty-First Int
Symposium
25-27 June 1991 Page(s):2 - 9
Digital Object Identifier 10.1109/FTCS.1991.146625

AbstractPlus | Full Text: PDF(688 KB)   IEEE CNF

23.
Defect level prediction for I_{DDQ} testing
Okuda, Y.; Kubota, I.; Watanabe, M.;
Test Conference, 1998. Proceedings. International

18-23 Oct. 1998 Page(s):900 - 909
Digital Object Identifier 10.1109/TEST.1998.743281

AbstractPlus | Full Text: PDF(952 KB)   IEEE CNF

24. **Application of extension theory to PD pattern recognition in high-voltage transformers**
Mang-Hui Wang; Chih-Yung Ho;
Power Delivery, IEEE Transactions on
Volume 20, Issue 3, July 2005 Page(s):1939 - 1946
Digital Object Identifier 10.1109/TPWRD.2005.848673

AbstractPlus | Full Text: PDF(1168 KB)   IEEE JNL

25. **Ensuring the operational health of droplet-based microelectrofluidic bios**
Fei Su; Ozev, S.; Chakrabarty, K.;
Sensors Journal, IEEE
Volume 5, Issue 4, Aug. 2005 Page(s):763 - 773
Digital Object Identifier 10.1109/JSEN.2005.848127

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Important Medical Product Safety Information - **2000**. ... for Carticel to second
line therapy for the **repair** of cartilage **defects** of the femoral condyle. ...
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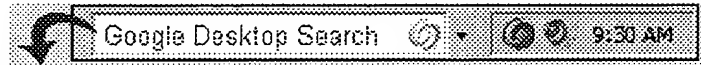www.epa.gov/otaq/url-fr/fr25au99.pdf - <u>Similar pages</u>

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